



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. ....09/653,156  
Confirmation No.....4650  
Filing Date .....August 31, 2000  
Inventor.....Vishnu K. Agarwal et al.  
Assignee.....Micron Technology, Inc.  
Group Art Unit.....2813  
Examiner .....Thanh T. Nguyen  
Customer No. ....021567  
Attorney's Docket No. ....MI22-1518  
Title:.....Enhanced Surface Area Capacitor Fabrication Methods

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Reference -See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed together with the filing of a Request for Continued Examination (RCE) Application. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee.

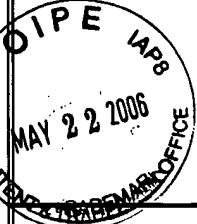
Citation of these references is respectfully requested.

Respectfully submitted,

Dated: 22 May 2006

By:

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1518	SERIAL NO. 09/653,156			
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				APPLICANT: Vishnu K. Agarwal et al.				
				FILING DATE August 31, 2000	GROUP 2813			
<b>U.S. PATENT DOCUMENTS</b>								
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	2002/0153579 A1	10/2002	Yamamoto				
	AB	2002/0182820 A1	12/2002	Choi et al.				
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	AF	6,849,505 B2	02/2005	Lee et al.				
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	AI	5,006,956	04/1991	Kawakita et al.				
	AJ							
	AK							
	AL							
	AM							
<b>FOREIGN PATENT DOCUMENTS</b>								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AN	JP 2002/222934 A	08/2002	Japan				
	AO							
<b>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AP							
	AQ							
	AR							
EXAMINER		DATE CONSIDERED						
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								